



OIML Certification System (OIML-CS) Implementation Accreditation in Legal Metrology

Legal Metrology Experts

Legal Metrology Experts validated by the OIML-CS Management Committee to participate in Accreditation and Peer Assessments under the OIML-CS

Expert Name	Country	OIML Recommendation																			Assessment Experience										
		R 16	R 21	R 35	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 111	R 117	R 126	R 129	R 134	R 137	R 139	R 148	R 149	ISO/IEC 17020	ISO/IEC 17025	ISO/IEC 17065			
CHEN, Yi	AU					✓	✓	✓			✓			✓	✓											✓					
ZAMORA, Mario	AU																	✓													
MATEUS SANCHEZ, Juan Carlos ¹	BR	✓	✓	✓							✓		✓			✓	✓									✓					
COUVREUR, Gulian	CH					✓	✓	✓	✓	✓	✓			✓	✓					✓		✓				✓	✓	✓			
DE HUU, Marc	CH																										✓				
NIEDERHAUSER, Bernhard	CH																		✓								✓				
HU, Manhong	CN					✓	✓		✓		✓				✓					✓											
JIANG, Jile	CN							✓																							
SHI, Leibing	CN				✓																										
WANG, Jian	CN						✓				✓																	✓			
YANG, Jing	CN																		✓												
YANG, Youtao	CN																			✓											
ZHONG, Ruilin	CN						✓	✓		✓		✓				✓				✓											
ZHOU, Shaoyuan	CN				✓																										

1 For EMC tests only

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		R 16	R 21	R 35	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 111	R 117	R 126	R 129	R 134	R 137	R 139	R 148	R 149	ISO/IEC 17020	ISO/IEC 17025	ISO/IEC 17065
BENKOVA, Miroslava	CZ					✓																				✓		
BÍLEK, Jindřich	CZ												✓													✓		
KALOUS, Stanislav	CZ																									✓		
KRIZ, Ivan	CZ					✓	✓	✓				✓		✓	✓											✓		
VALENTA, Tomáš	CZ																									✓		✓
KRAMER, Rainer	DE																									✓		
ROSE, Jürgen	DE									✓																✓	✓	✓
SCHWABE, Timo	DE							✓																				
JENSEN, Jens Hovgård	DK						✓	✓		✓		✓				✓			✓	✓								
BRUN, Christophe	FR																	✓				✓					✓	
DELETTÉ, Laetitia	FR																		✓								✓	
LOPEZ, Luc ²	FR	✓					✓			✓	✓	✓					✓										✓	
MOREL, Emeric	FR					✓																					✓	
PEREZ, Reuven	IL					✓																					✓	
AGARWAL, Ashutosh	IN	✓				✓	✓	✓	✓	✓			✓				✓				✓	✓				✓		
PIROVANO, Miriam	IT																				✓					✓		✓
SESTINI, Maria Cristina	IT																			✓						✓	✓	
ZOTTI, Lucio	IT					✓		✓		✓		✓						✓								✓	✓	
AZAMI, Nobuhiko	JP								✓																			
ITO, Takeshi	JP																	✓									✓	
NAGANO, Tomohiro	JP												✓														✓	
OTANI, Satoshi	JP												✓														✓	
TANAKA, Yoshitada	JP									✓																		

2 Limited to assessments of OIML Issuing Authorities

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		R 16	R 21	R 35	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 111	R 117	R 126	R 129	R 134	R 137	R 139	R 148	R 149	ISO/IEC 17020	ISO/IEC 17025	ISO/IEC 17065
BEUMER, Erik	NL					✓					✓													✓			✓	
BOEREBOOM, Hans	NL					✓																						
CLOO, Marcel	NL				✓																						✓	
KOK, Paul	NL	✓				✓	✓		✓		✓		✓					✓	✓	✓							✓	✓
MEIJER, Mathias	NL	✓				✓		✓			✓															✓	✓	
ROOIJ, Paul van	NL					✓					✓		✓					✓			✓	✓					✓	
SCHOLTEN, Roy	NL						✓		✓		✓					✓			✓		✓					✓		
SOEKHOE, Satish	NL																	✓			✓	✓					✓	
TJOA, Aldemar	NL				✓	✓	✓				✓	✓	✓				✓		✓	✓						✓		
VERMEUL, Yvo	NL					✓					✓						✓			✓						✓		
WIJNGAARDEN, Carl van	NL																			✓							✓	
YILMAZ, Baris	NL						✓				✓								✓							✓	✓	
BOBBALA, Srinivas	NZ										✓							✓									✓	
HATTINGH, Jaco	NZ					✓						✓															✓	
KÄLLGREN, Hakan	SE						✓	✓	✓	✓		✓			✓	✓										✓	✓	
GRUM, Matej	SI						✓	✓		✓		✓			✓	✓										✓	✓	
PREMUŠ, Aleksander	SI	✓		✓																							✓	✓
KRAL, Stefan	SK						✓																				✓	✓
MAZÚR, Viliam	SK					✓																					✓	
AYDEMIR, Bülent	TR						✓	✓	✓	✓		✓			✓	✓				✓							✓	
KAÇMAZ, Sevda	TR						✓	✓	✓	✓		✓			✓	✓				✓							✓	
GLAS, Gregory	UK						✓	✓		✓		✓			✓	✓				✓						✓	✓	
JAMES, Ivor	UK																✓											
JI, Wei	UK	✓					✓	✓	✓	✓		✓						✓	✓							✓	✓	
WARD, Christine	UK		✓									✓														✓		